

DIN ISO 16129



ICS 71.040.40

Einsprüche bis 2020-01-29

Entwurf

**Chemische Oberflächenanalyse –
Röntgenphotoelektronenspektroskopie –
Verfahren zur Bestimmung des täglichen Leistungsvermögens eines
Röntgenphotoelektronenspektrometers (ISO 16129:2018);
Text Englisch**

Surface chemical analysis –
X-ray photoelectron spectroscopy –
Procedures for assessing the day-to-day performance of an X-ray photoelectron
spectrometer (ISO 16129:2018);
Text in English

Analyse chimique des surfaces –
Spectroscopie de photoélectrons X –
Modes opératoires d'évaluation de la performance au jour le jour d'un spectromètre de
photoélectrons X (ISO 16129:2018);
Texte en anglais

Anwendungswarnvermerk

Dieser Norm-Entwurf mit Erscheinungsdatum 2019-11-29 wird der Öffentlichkeit zur Prüfung und Stellungnahme vorgelegt.

Weil die beabsichtigte Norm von der vorliegenden Fassung abweichen kann, ist die Anwendung dieses Entwurfs besonders zu vereinbaren.

Stellungnahmen werden erbeten

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Gesamtumfang 26 Seiten

DIN-Normenausschuss Materialprüfung (NMP)

Inhalt

	Seite
Nationales Vorwort	3
Nationaler Anhang NA (informativ) Literaturhinweise	4

Nationales Vorwort

Dieses Dokument enthält die Internationale Norm ISO 16129:2018, die vom Technischen Komitee ISO/TC 201 „Surface chemical analysis“ erarbeitet wurde, dessen Sekretariat von JISC (Japan) gehalten wird.

Das zuständige deutsche Normungsgremium ist der Arbeitsausschuss NA 062-08-16 AA „Chemische Oberflächenanalyse und Rastersondenmikroskopie“ im DIN-Normenausschuss Materialprüfung (NMP).

Dieses Dokument enthält unter Berücksichtigung des DIN-Präsidialbeschlusses 1/2004 nur die englische Fassung von ISO 16129:2018.

Für die in diesem Dokument zitierten internationalen Dokumente wird im Folgenden auf die entsprechenden deutschen Dokumente hingewiesen:

ISO 15472 siehe DIN ISO 15472

ISO 18115-1 siehe DIN ISO 18115-1

Nationaler Anhang NA (informativ)

Literaturhinweise

DIN ISO 15472, *Chemische Oberflächenanalyse — Röntgenphotoelektronenspektrometer — Kalibrierung der Energieskala*

DIN ISO 18115-1, *Chemische Oberflächenanalyse — Vokabular — Teil 1: Allgemeine Begriffe und Begriffe für die Spektroskopie*

Contents

Page

Foreword	iv
Introduction	v
1 Scope	1
2 Normative references	1
3 Terms, definitions and abbreviations	1
4 Initial approach	1
5 Initial instrument calibration, alignment and assessment	2
6 Test specimen selection	2
6.1 General information	2
6.2 The conductive specimen	3
6.3 The non-conductive specimen	3
6.4 Specimen for assessing the X-ray source	4
7 Collection of reference data	5
7.1 General information	5
7.2 Rapid test of the instrument using a conductive specimen	5
7.2.1 Specimen mounting and pre-treatment	5
7.2.2 Survey spectrum	5
7.2.3 High-resolution spectrum	7
7.3 Rapid test of the instrument using a non-conductive specimen	8
7.3.1 Specimen mounting and positioning	8
7.3.2 High-resolution spectrum	8
7.4 Rapid test of the X-ray source using a phosphor specimen	8
7.5 Rapid test of the X-ray source using a uniform conductive specimen	9
8 Collection of subsequent performance data	9
9 Analysis of the performance data	10
9.1 General information	10
9.2 Survey spectrum	10
9.3 High-resolution spectrum from the conductive specimen	10
9.4 High-resolution spectrum from the non-conductive specimen	10
9.5 Images from the phosphor specimen	10
9.6 Images from the uniform conductive specimen	10
9.7 Spectrum ratios	11
10 Control charts	15
Bibliography	18

Foreword

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The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

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For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT) see www.iso.org/iso/foreword.html.

This document was prepared by Technical Committee ISO/TC 201, *Surface chemical analysis*, Subcommittee SC 7, *Electron spectroscopies*.

This second edition cancels and replaces the first edition (ISO 16129:2012), which has been technically revised.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

Introduction

XPS instruments are complex, and unsatisfactory performance is not always obvious to an operator. It is therefore necessary to provide a test for the correct operation of the system that can be performed regularly and frequently without interfering excessively with the normal work of the laboratory.

A full diagnostic test can require many hours or even days; such a test can be appropriate only when the instrument is known to have a fault that needs to be remedied or following a major maintenance procedure. Data acquired before a problem is uncovered become suspect if the spectrometer has not been routinely tested, leading to a loss of confidence in those data. If a regular check of the instrument is made, changes in performance can be monitored and corrective action taken in good time to ensure that the data supplied are fit for purpose. In the event that a serious fault is uncovered, then only the data since the last check can be in doubt and need to be repeated.

The purpose of this document is to provide users with a procedure which is not excessively time-consuming so that it can be completed on a regular and frequent basis – daily if required. The user will then gain an awareness of the current characteristics of the instrument so that a decision can be made as to whether or not a more complete and time-consuming action is required to return the instrument to a satisfactory level of performance.

This procedure is intended to be applied to an XPS instrument that has been correctly calibrated and aligned in accordance with ISO standards or manufacturer's instructions. It is designed to highlight aspects of the instrument's characteristics that differ significantly from those that were measured immediately following the calibration procedure. The procedure does not show how the instrument can be returned to its original state. Instead, it guides the user to possible areas of concern. The procedure provides data that can be used in control charts, allowing trends to be observed and acted upon before data quality deteriorates to an unacceptable level for the needs of the analyst.

– *Entwurf* –